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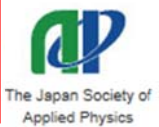
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- NEW** 2013/05/27 [Post Deadline Paper\(PDP\) Submission Started.](#)
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Important Dates

- Paper Submission**
Start : December 10, 2012
End : ~~February 4, 2013~~ **February 22, 2013**
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- Acceptance Notification** ~~End of March, 2013~~
Beginning of April, 2013
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An Equivalent Circuit with a Noise Source for 850-nm Si Avalanche Photodetector and Optimal Design of Si OEIC Receiver

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Abstract

Equivalent circuit model including noise current source is developed for 850-nm Si avalanche photodetector (APD). The measured APD signal-to-noise characteristics are modeled with circuit parameters and used for realizing the optimal 12.5-Gbps Si OEIC receiver.

I. INTRODUCTION

For short-reach optical interconnect applications, high-performance optoelectronic integrated circuit (OEIC) receivers are highly desirable. Monolithic integration of Si electronics with Si photodetector provides performance enhancement as well as cost effectiveness [1]. Several Si OEIC receivers have been reported [2], [3]. We have demonstrated OEIC receivers with on-chip Si avalanche photodetector (APD) in standard Si technology [4], [5]. In order to optimize OEIC receiver design and, eventually, implement OEIC receiver as a sub-block of much larger Si electronic systems, it is essential to develop design methodology in which the optical devices are co-designed and co-simulated with electronic circuits on Si platform. For this goal, we have previously reported an equivalent circuit model of Si APD [6] that allows unified circuit-level simulation for the entire OEIC receiver.

In this paper, we further enhance the model by adding the APD noise characteristics. This is an important task as APDs provide much enhanced noises as well as signals. APD noise characteristics are measured for different reverse bias voltages, and the results are modeled by a noise current source. This allows us design optimization of the entire OEIC receiver. A 12.5-Gbps 850-nm OEIC receiver is successfully realized with such design optimization.

II. EQUIVALENT CIRCUIT MODEL FOR SI APD

Fig. 1 shows a simplified block diagram of Si OEIC receiver. An APD equivalent circuit model is composed of parasitic RLC components and a signal current source as well as a noise current source. APD noise characteristics can be modeled with Gaussian distribution in the case of Si APD having small excess noise factors [7]. The $I_{s,pp,APD}$ represents peak-to-peak signal current, and $I_{n,rms,APD}$ represents root mean square (rms) noise current. Fig. 2 shows the measured $I_{s,pp,APD}$ and $I_{n,rms,APD}$ of our APD as a function of reverse bias voltage (V_R) at

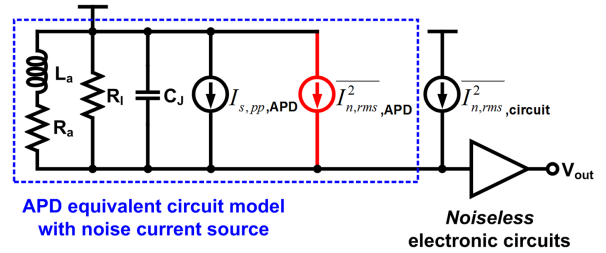


Fig. 1. Simplified block diagram of Si OEIC receiver.

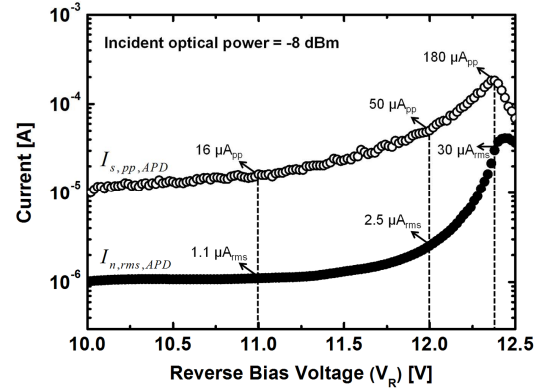


Fig. 2. Measured APD signal and noise characteristics.

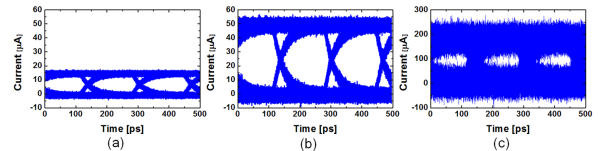


Fig. 3. Simulated eye diagrams with different reverse bias voltages (V_R) of (a) 11.0 V, (b) 12.0 V, and (c) 12.4 V.

incident optical power of -8 dBm. For signal measurement, 1-GHz sinusoidal signal is modulated by using an 850-nm laser diode and an external electro-optic modulator. The modulated light is transmitted through multimode fiber, and injected into the APD using a lensed fiber. For noise measurement, noise power spectral density at 1 GHz is measured without any RF signal applied to the modulator. With the increasing V_R , signal current is enhanced due to avalanche gain, and noise current is also increased due to avalanche noise. Fig. 3 show the simulated eye diagrams of APD output currents at three different bias voltages of 11.0, 12.0, and 12.4 V, respectively. This simulation is done with Spectre circuit simulator in Cadence by adding the APD noise model with Verilog-A. As shown in Fig. 3, signal amplitude is increased with the increasing V_R , however, signal quality

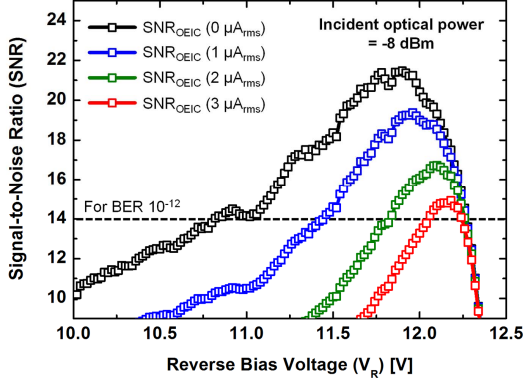


Fig. 4. Estimated signal-to-noise ratio of APD and OEIC receiver.

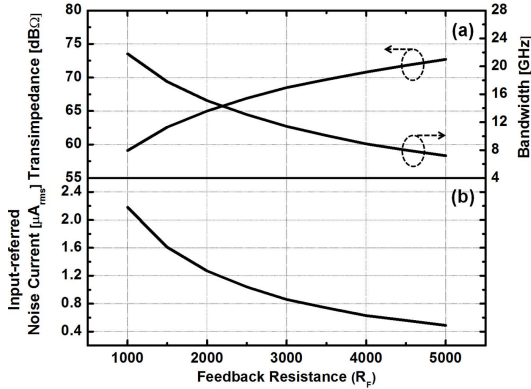


Fig. 5. Simulation results of the designed shunt-feedback TIA.

can be degraded due to increased avalanche noise.

III. OEIC RECEIVER DESIGN OPTIMIZATION

As shown in Fig. 1, the noise characteristics of the entire electronic circuit can be modeled with a circuit noise current source with $I_{n,rms,circuit}$ represents rms input-referred noise current of electronic circuits. Then, the signal-to-noise ratio (SNR) of the OEIC receiver is given as:

$$SNR_{OEIC}(V_R) = \frac{I_{s,pp,APD}(V_R)}{\sqrt{I_{n,rms,APD}^2(V_R) + I_{n,rms,circuit}^2}}. \quad (1)$$

Fig. 4 shows the estimated SNR_{OEIC} for different $I_{n,rms,circuit}$ of 0, 1, 2, and 3 μA_{rms} . To achieve a bit-error rate (BER) less than 10^{-12} , SNR of about 14 is required, and therefore, $I_{n,rms,circuit}$ should be minimized to less than 1 μA_{rms} . This figure also shows that the APD bias should be carefully controlled in order to achieve the optimal OEIC receiver SNR.

In order to achieve high gain and low-noise transimpedance amplifier (TIA), the shunt-feedback architecture is used [8]. Fig. 5 shows simulation results of our TIA as a function of feedback resistance (R_F). In order to achieve $I_{n,rms,circuit}$ less than 1 μA_{rms} , R_F larger than 2.5 k Ω is needed. We used R_F of 3 k Ω , which gives $I_{n,rms,circuit}$ of 0.86 μA_{rms} , transimpedance of 68.5 dB Ω , and bandwidth of 11.4 GHz in Spectre simulation.

IV. MEASUREMENT RESULTS

With above mentioned design optimization, we realized an OEIC receiver with monolithically integrated

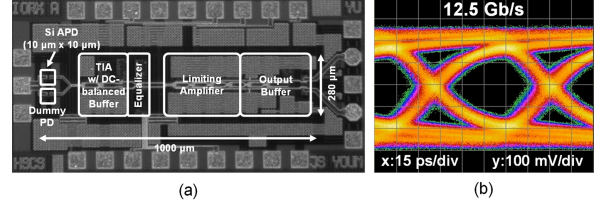


Fig. 6. (a) Chip photograph and (b) Measured eye diagram.

Si APDs in standard 0.25- μm SiGe BiCMOS technology [5]. With the fabricated OEIC receiver, 12.5-Gbps broadband optical data is successfully detected. Fig. 6(a) and (b) show chip photograph and measured 12.5-Gbps eye diagram, respectively. To the best of our knowledge, our OEIC receiver achieves the highest data rate among previously reported Si OEIC receivers.

V. CONCLUSIONS

We report an 850-nm Si APD equivalent circuit model including the noise current source and the process of design optimization of Si OEIC receiver. With the fabricated OEIC receiver, we successfully achieve 12.5-Gbps broadband optical data transmission with BER less than 10^{-12} .

ACKNOWLEDGMENT

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